



## [ThPM1-06] Raman Metrology 1

**Date / Time** Aug. 30 (Thu.), 2018 / 14:30-16:30

**Place** 301 (Room E)

### [ThPM1-06-K-1] (Keynote)

14:30-15:00

#### **Raman Metrology: a Community Effort towards Standardization and Traceability**

Erlon H Martins Ferreira

Inmetro - National Institute of Metrology, Quality and Technology, Brazil

### [ThPM1-06-I-2] (Invited)

15:00-15:20

#### **Comparison of Raman Shifts Obtained under Different Instruments and Conditions**

Nobuyasu Itoh<sup>1,2</sup>, Katsuhiro Shirono<sup>1,2</sup>, and Toshiyuki Fujimoto<sup>1,2</sup>

<sup>1</sup>National Metrology Institute of Japan (NMIJ), Japan, <sup>2</sup>National Institute of Advanced Industrial Science and Technology (AIST), Japan

### [ThPM1-06-I-3] (Invited)

15:20-15:40

#### **Raman Standardization for Raman Shift and Intensity Calibration of Spectrometer**

Sungwoon Lee and Hyuksang Kwon

KRISS, Korea

### [ThPM1-06-I-4] (Invited)

15:40-16:00

#### **A Novel Approach for Accurate Tip-Enhanced Raman Spectroscopy (TERS) Enhancement Factor Quantification**

Alessio Sacco<sup>1,2</sup>, Chiara Portesi<sup>1</sup>, Luisa Mandrile<sup>1</sup>, Andrea Mario Giovannozzi<sup>1</sup>, and Andrea Mario Rossi

<sup>1</sup>Istituto Nazionale di Ricerca Metrologica, Italy, <sup>2</sup>Politecnico di Torino, Italy

### [ThPM1-06-O-5]

16:00-16:15

#### **Low-frequency Raman Line-Shape: A Convolution of Quantum Confinement and Fano Interference**

Vivek Kumar

Indian Institute of Information Technology Design and Manufacturing Kancheepuram, India